

**Search Notes**

Application/Control No.

10/721,573

Examiner

Phallaka Kik

Applicant(s)/Patent under  
Reexamination

LOONG, LOW YAU

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	16,17,18,3 2,7	10/28/2005	PK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
716	16,17,18	10/28/2005	PK
716	3,2,7	10/28/2005	PK
--USPGPUB (see attached)		10/28/2005	PK

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
BRS (EAST) --USPAT, USPGPUB Class/Sub searched: 716/1-18 (see attached)	10/28/2005	PK
--EPO, JPO, IBM TDB, Derwent (see attached)	10/28/2005	PK
IEE/IEEE Xplore (see attached)	10/28/2005	PK